

<b>FORM PTO-1449</b> <b>U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</b>  List of Information Cited by Applicant  Page 1 of 1	<b>ATTY. DOCKET NO.</b> SURR.86	<b>SERIAL NO.</b> 10/056,808
	<b>APPLICANT</b> NATAN	
	<b>FILING DATE</b> JANUARY 25, 2002	<b>GROUP</b> 1743

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js	AA	09/378,259	8/20/99	Dietz et al.			
j	AB	09/558,094	4/26/00	Dietz et al.			
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	AH	09/969,518	10/02/01	Stonas et al.			
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	AM	Brazdil & Yeager, <i>J. Phys. Chem.</i> (1981) 85: 995-1004	
	AN	Byahut & Furtak, <i>Langmuir</i> (1991) 7: 508-513	
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	AX	Sun et al., <i>J. Mater. Sci.</i> (2000) 35: 1097-1103	
	AY	Switzer et al., <i>J. Am. Chem. Soc.</i> (1998) 120: 3530-3531	
	js	AZ	Ung et al., <i>Langmuir</i> (1998) 14: 3740-3748
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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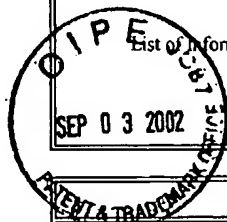
<b>FORM PTO-1449</b> <b>U.S. DEPARTMENT OF</b> <b>COMMERCE PATENT</b> <b>AND TRADEMARK</b> <b>OFFICE</b>  List of Information Cited by Applicant Page 1 of 1	<b>ATTY. DOCKET NO.</b> Surr. 86	<b>SERIAL NO.</b> 10/056,808
	<b>APPLICANT</b> NATAN	<b>COPY OF PAPERS</b> <b>ORIGINALLY FILED</b>
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	AM	Felidj et al. (1998) New J. Chem. 725-732
	AN	Freeman et al. (1996) 100:718-724
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